Individual article citation record according to ISI Web of knowledge

Number of publications: 12
Sum of the Times Cited: 103
Sum of Times Cited without self-citations: 80

Citing Articles: 57
Citing Articles without self-citations: 48
Average Citations per Item: 8.58

	2010	2011	2012	2013	Total	Average Citations per Year
	12	38	18	35	103	20.60
1. **Imaging dielectric relaxation in nanostructured polymers by frequency modulation electrostatic force microscopy** By: Riedel, C.; Sweeney, R.; Israeloff, N. E.; et al. APPLIED PHYSICS LETTERS Volume: 96 Issue: 21 Article Number: 213110 Published: MAY 24 2010	2	8	3	9	22	4.40
2. **Nanodielectric mapping of a model polystyrene-poly(vinyl acetate) blend by electrostatic force microscopy** By: Riedel, C.; Arinero, R.; Tordjeman, Ph; et al. PHYSICAL REVIEW E Volume: 81 Issue: 1 Article Number: 010801 Part: 1 Published: JAN 2010	2	9	4	7	22	4.40
3. **Determination of the nanoscale dielectric constant by means of a double pass method using electrostatic force microscopy** By: Riedel, C.; Arinero, R.; Tordjeman, Ph.; et al. JOURNAL OF APPLIED PHYSICS Volume: 106 Issue: 2 Article Number: 024315 Published: JUL 15 2009	5	7	2	7	21	3.50
4. **Nanoscale dielectric properties of insulating thin films: From single point measurements to quantitative images** By: Riedel, C.; Schwartz, G. A.; Arinero, R.; et al. Conference: 11th International Scanning Probe Microscopy Conference (ISPM) Location: Madrid, SPAIN Date: JUN 17-19, 2009 ULTRAMICROSCOPY Volume: 110 Issue: 6 Pages: 634-638 Published: MAY 2010	0	4	0	3	7	1.40
5. **Rouse-Model-Based Description of the Dielectric Relaxation of Nonentangled Linear 1,4-cis-Polyisoprene** By: Riedel, Clement; Alegria, Angel; Tordjeman, Philippe; et al. MACROMOLECULES Volume: 42 Issue: 21 Pages: 8492-8499 Published: NOV 10 2009	2	3	1	1	7	1.17
6. **Broadband nanodielectric spectroscopy by means of amplitude modulation electrostatic force microscopy (AM-EFM)** By: Schwartz, G. A.; Riedel, C.; Arinero, R.; et al. ULTRAMICROSCOPY Volume: 111 Issue: 8 Pages: 1366-1369 Published: JUL 2011	0	0	1	5	6	1.50
7. **High and low molecular weight crossovers in the longest relaxation time dependence of linear cis-1,4 polyisoprene by dielectric relaxations** By: Riedel, Clement; Alegria, Angel; Tordjeman, Philippe; et al. Conference: Gennes Discussion Conference on From Reputation to Glossy Materials - Gennes Pioneering Work in Rheology and Recent Developments Location: Chamonix, FRANCE Date: FEB 01-05, 2009 Sponsor(s): French Grp Rheol; European Soc Rheol RHEOLOGICA ACTA Volume: 49 Issue: 5 Special Issue: SI Pages: 507-512 Published: MAY 2010	0	2	3	1	6	1.20
8. **Numerical study of the lateral resolution in electrostatic force microscopy for dielectric samples** By: Riedel, C.; Alegria, A.; Schwartz, G. A.; et al. NANOTECHNOLOGY Volume: 22 Issue: 28 Article Number: 285705 Published: JUL 15 2011	0	2	1	2	5	1.25
9. **Dielectric properties of thin insulating layers measured by Electrostatic Force Microscopy** By: Riedel, C.; Arinero, R.; Tordjeman, Ph.; et al. EUROPEAN PHYSICAL JOURNAL-APPLIED PHYSICS Volume: 50 Issue: 1 Article Number: 10501 Published: APR 2010	1	3	0	0	4	0.80
10. **Contrast inversion in electrostatic force microscopy imaging of trapped charges: tip-sample distance and dielectric constant dependence** By: Riedel, C.; Alegria, A.; Arinero, R.; et al. NANOTECHNOLOGY Volume: 22 Issue: 34 Article Number: 345702 Published: AUG 26 2011	0	0	2	0	2	0.50
11. **On the use of electrostatic force microscopy as a quantitative subsurface characterization technique: A numerical study** By: Riedel, C.; Alegria, A.; Schwartz, G. A.; et al. APPLIED PHYSICS LETTERS Volume: 99 Issue: 2 Article Number: 023101 Published: JUL 11 2011	0	0	1	0	1	0.25
12. **Numerical simulations of electrostatic interactions between an atomic force microscopy tip and a dielectric sample in presence of buried nano-particles** By: Arinero, R.; Riedel, C.; Guasch, C. JOURNAL OF APPLIED PHYSICS Volume: 112 Issue: 11 Article Number: 114313 Published: DEC 1 2012	0	0	0	0	0	0.00